

TOSHIBA Field Effect Transistor Silicon P Channel MOS Type (U-MOSII)

TPC8303

Lithium-Ion Battery Applications
 Portable Equipment Applications
 Notebook PC Applications

- Low drain-source ON resistance : $R_{DS(ON)} = 27 \text{ m}\Omega$ (typ.)
- High forward transfer admittance : $|Y_{fs}| = 7 \text{ S}$ (typ.)
- Low leakage current : $I_{DSS} = -10 \text{ }\mu\text{A}$ (max.) ($V_{DS} = -30 \text{ V}$)
- Enhancement mode : $V_{th} = -0.8 \sim -2.0 \text{ V}$ ($V_{DS} = -10 \text{ V}$, $I_D = -1 \text{ mA}$)

Absolute Maximum Ratings (Ta = 25°C)

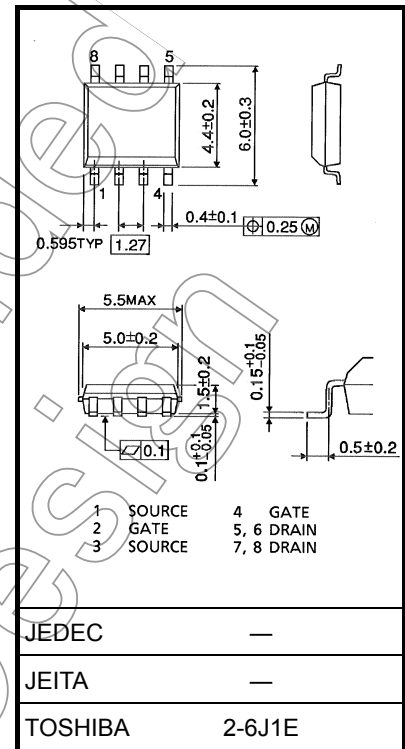
Characteristics		Symbol	Rating	Unit
Drain-source voltage		V_{DS}	-30	V
Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)		V_{DGR}	-30	V
Gate-source voltage		V_{GSS}	± 20	V
Drain current	DC (Note 1)	I_D	-4.5	A
	Pulse (Note 1)	I_{DP}	-18	
Drain power dissipation ($t = 10\text{s}$) (Note 2a)	Single-device operation (Note 3a)	$P_{D(1)}$	1.5	W
	Single-device value at dual operation (Note 3b)	$P_{D(2)}$	1.0	
Drain power dissipation ($t = 10\text{s}$) (Note 2b)	Single-device operation (Note 3a)	$P_{D(1)}$	0.75	W
	Single-device value at dual operation (Note 3b)	$P_{D(2)}$	0.45	
Single-pulse avalanche energy (Note 4)		E_{AS}	26	mJ
Avalanche current		I_{AR}	-4.5	A
Repetitive avalanche energy Single-device value at operation (Note 2a, Note 3b, Note 5)		E_{AR}	0.10	mJ
Channel temperature		T_{ch}	150	°C
Storage temperature range		T_{stg}	-55~150	°C

Note: For Notes 1 to 5, see the next page.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

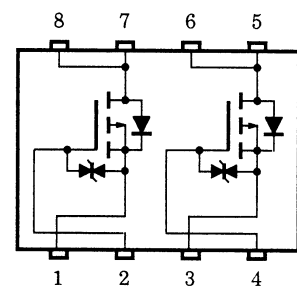
This transistor is an electrostatic-sensitive device. Handle with care.

Unit: mm



Weight: 0.08 g (typ.)

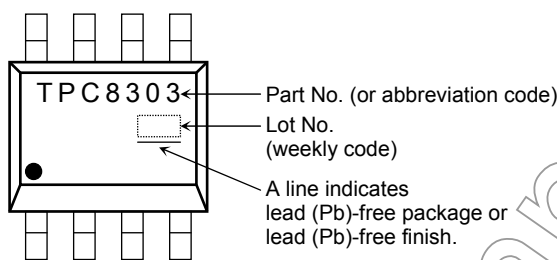
Circuit Configuration



Thermal Characteristics

Characteristics		Symbol	Max	Unit
Thermal resistance, channel to ambient (t = 10s)	Single-device operation (Note 3a)	$R_{th} (ch-a) (1)$	83.3	°C/W
	Single-device value at dual operation (Note 3b)	$R_{th} (ch-a) (2)$	125	
Thermal resistance, channel to ambient (t = 10s)	Single-device operation (Note 3a)	$R_{th} (ch-a) (1)$	167	
	Single-device value at dual operation (Note 3b)	$R_{th} (ch-a) (2)$	278	

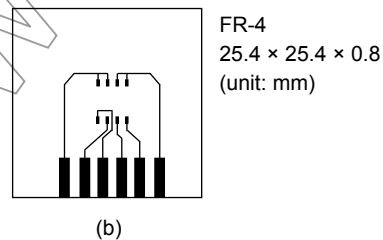
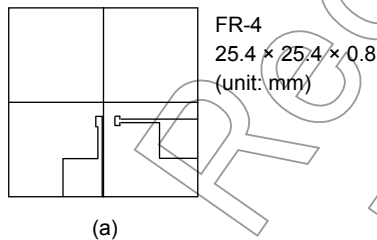
Marking (Note 6)



Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2:

- a) Device mounted on a glass-epoxy board (a) b) Device mounted on a glass-epoxy board (b)



Note 3:

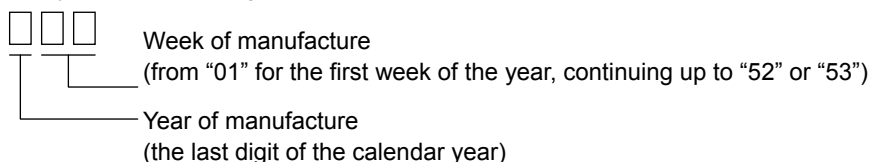
- a) The power dissipation and thermal resistance values shown are for a single device. (During single-device operation, power is applied to one device only.)
 b) The power dissipation and thermal resistance values shown are for a single device. (During dual operation, power is applied to both devices evenly.)

Note 4: $V_{DD} = -24 V$, $T_{ch} = 25^{\circ}C$ (initial), $L = 1.0 mH$, $R_G = 25 \Omega$, $I_{AR} = -4.5 A$

Note 5: Repetitive rating: pulse width limited by maximum channel temperature

Note 6: ● on lower left of the marking indicates Pin 1.

* Weekly code: (Three digits)

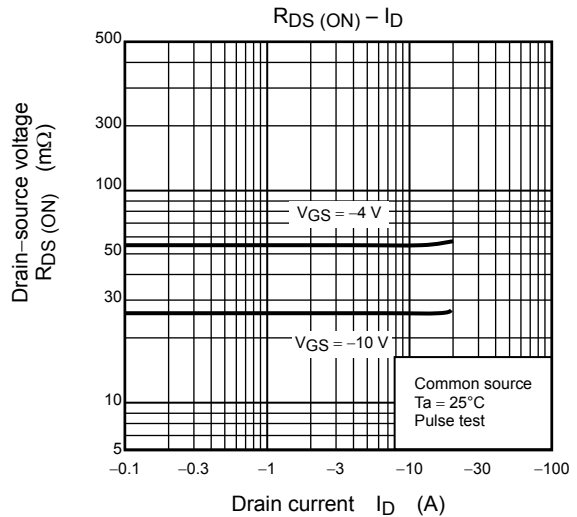
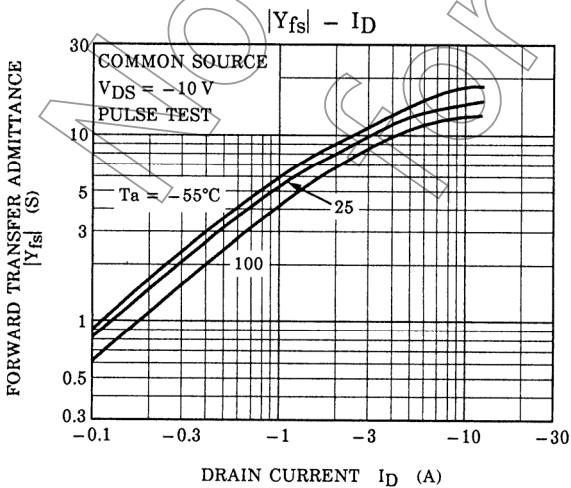
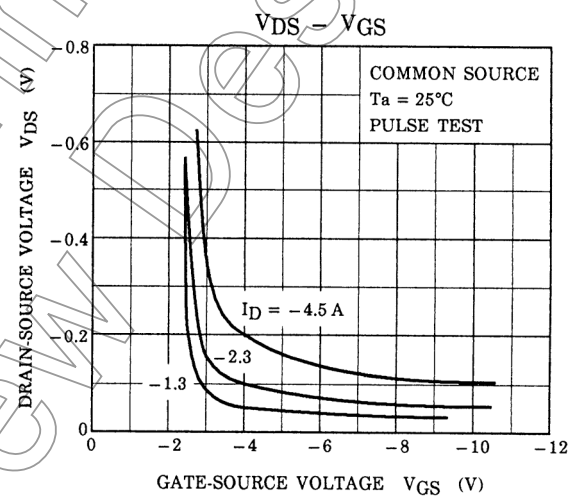
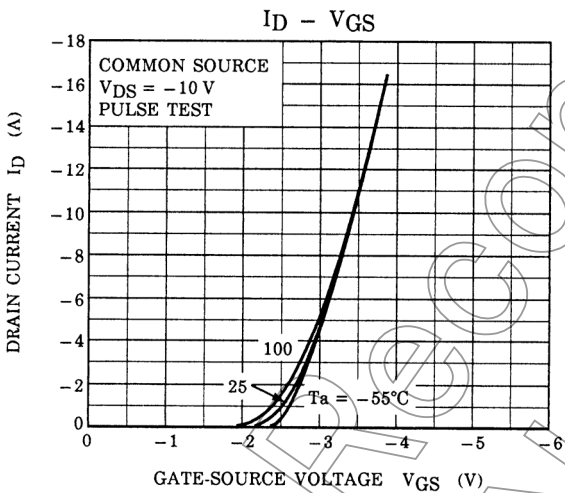
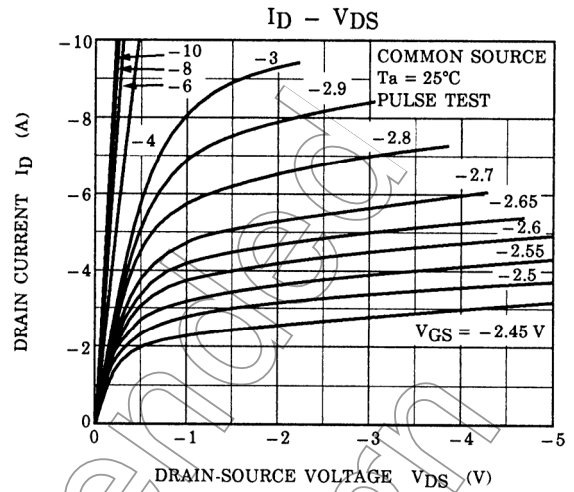
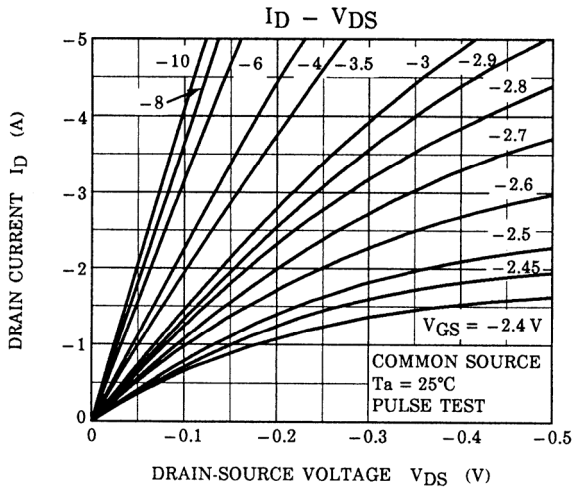


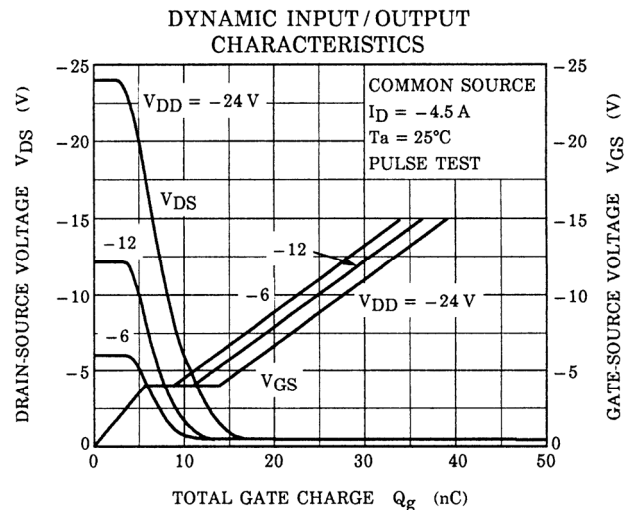
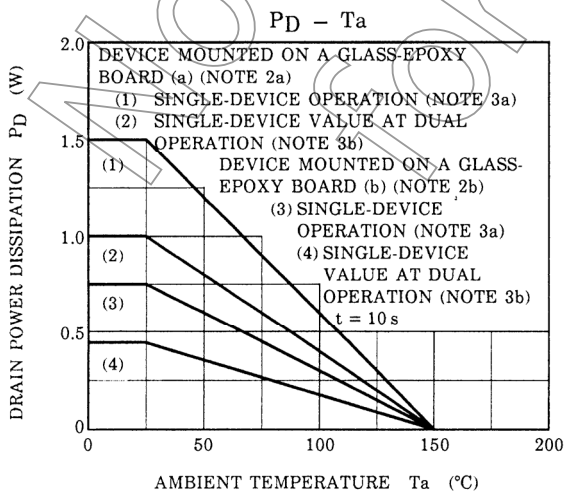
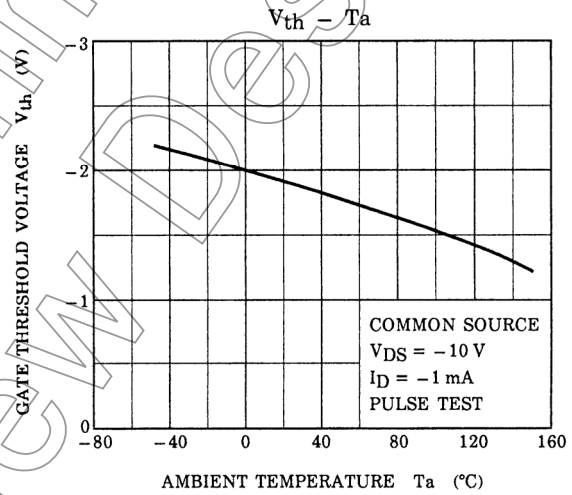
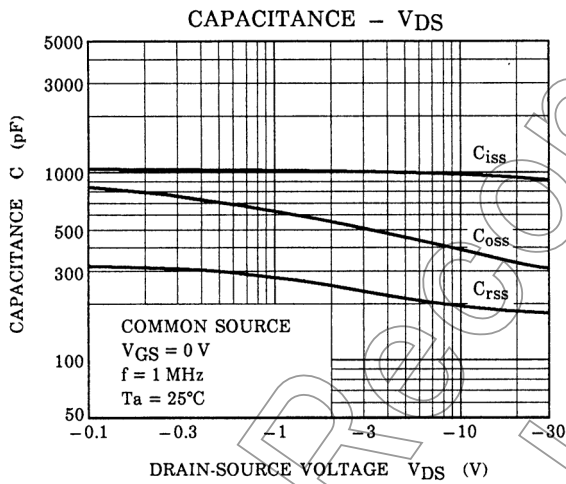
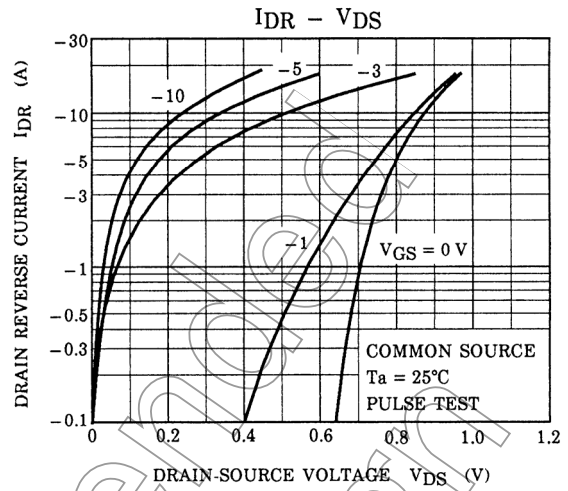
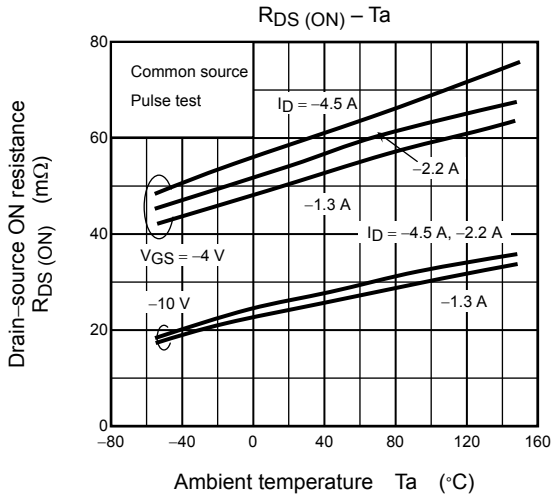
Electrical Characteristics (Ta = 25°C)

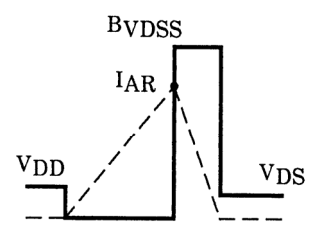
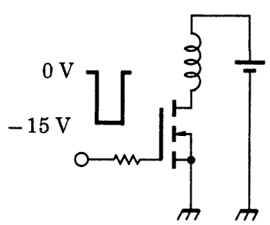
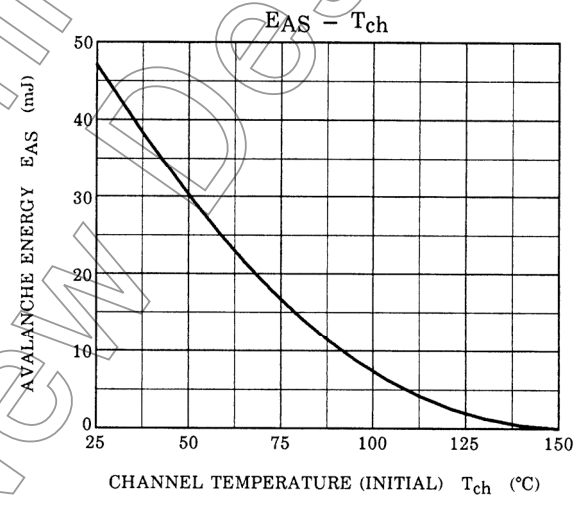
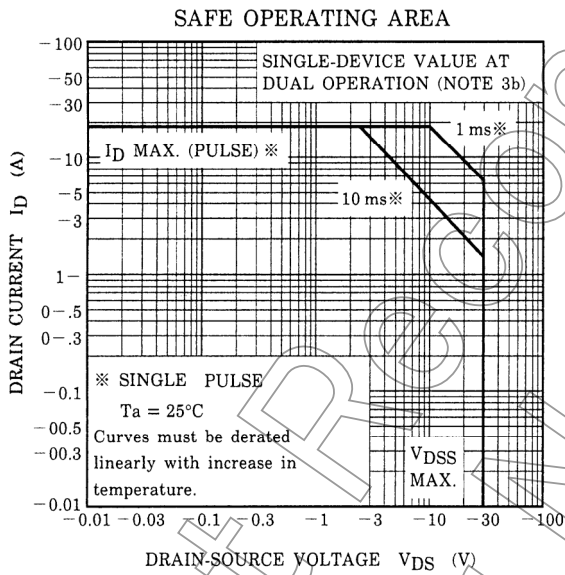
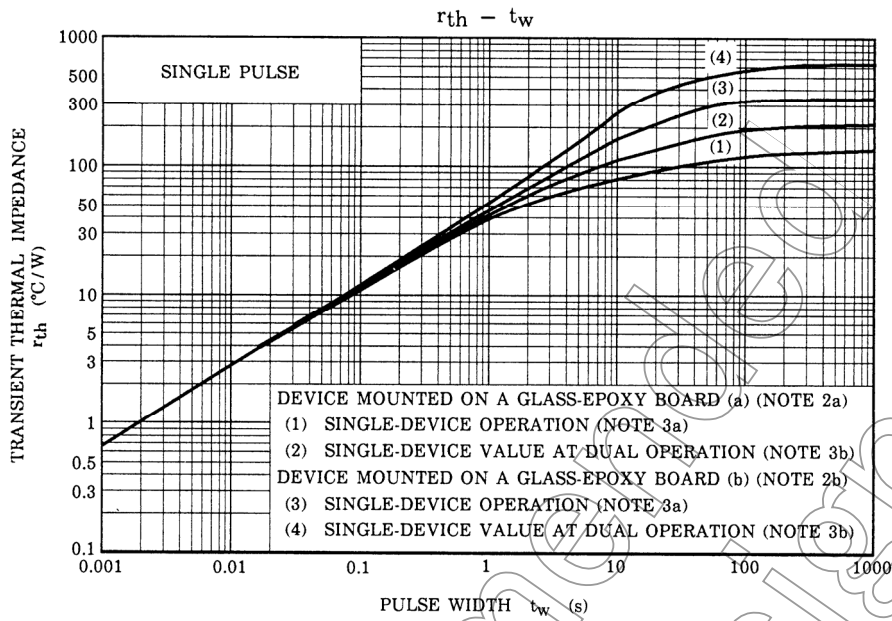
Characteristics		Symbol	Test Condition	Min.	Typ.	Max.	Unit
Gate leakage current		I_{GSS}	$V_{GS} = \pm 16\text{ V}, V_{DS} = 0\text{ V}$	—	—	± 10	μA
Drain cut-off current		I_{DSS}	$V_{DS} = -30\text{ V}, V_{GS} = 0\text{ V}$	—	—	-10	μA
Drain-source breakdown voltage		$V_{(BR)DSS}$	$I_D = -10\text{ mA}, V_{GS} = 0\text{ V}$	-30	—	—	V
		$V_{(BR)DSX}$	$I_D = -10\text{ mA}, V_{GS} = 20\text{ V}$	-15	—	—	
Gate threshold voltage		V_{th}	$V_{DS} = -10\text{ V}, I_D = -1\text{ mA}$	-0.8	—	-2.0	V
Drain-source ON resistance		$R_{DS(ON)}$	$V_{GS} = -4\text{ V}, I_D = -2.2\text{ A}$	—	55	65	m Ω
		$R_{DS(ON)}$	$V_{GS} = -10\text{ V}, I_D = -2.2\text{ A}$	—	27	35	
Forward transfer admittance		$ Y_{fs} $	$V_{DS} = -10\text{ V}, I_D = -2.2\text{ A}$	3.5	7	—	S
Input capacitance		C_{iss}	$V_{DS} = -10\text{ V}, V_{GS} = 0\text{ V}, f = 1\text{ MHz}$	—	970	—	pF
Reverse transfer capacitance		C_{rss}		—	180	—	
Output capacitance		C_{oss}		—	370	—	
Switching time	Rise time	t_r		—	17	—	ns
	Turn-on time	t_{on}		—	20	—	
	Fall time	t_f		—	75	—	
	Turn-off time	t_{off}		—	160	—	
Total gate charge (gate-source plus gate-drain)		Q_g	$V_{DD} \approx -24\text{ V}, V_{GS} = -10\text{ V}, I_D = -4.5\text{ A}$	—	28	—	nC
Gate-source charge		Q_{gs}		—	16	—	
Gate-drain ("miller") charge		Q_{gd}		—	12	—	

Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min.	Typ.	Max.	Unit
Drain reverse current	Pulse (Note 1)	I_{DRP}	—	—	—	-18	A
Forward voltage (diode)		V_{DSF}	$I_{DR} = -4.5\text{ A}, V_{GS} = 0\text{ V}$	—	—	1.2	V







$T_{ch} = 25^\circ\text{C}$ (Initial)
 Peak $I_{AR} = -4.5\text{ A}$, $R_G = 25\ \Omega$ $E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$
 $V_{DD} = -24\text{ V}$, $L = 1.0\text{ mH}$

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